Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/838,266	HIGASHIKATA ET AL.
	Examiner	Art Unit	
	Jason D. A. Vuong	2626	

SEARCHED

Class	Subclass	Date	Examiner
345		10/18/2004	JV
345	427	10/18/2004	JV
345	601	10/18/2004	JV
345	602	10/18/2004	JV
345	603	10/18/2004	JV
345	604	10/18/2004	JV
382	167	10/18/2004	JV
358	518	10/18/2004	JV
358	519	10/18/2004	JV
358	520	10/18/2004	JV
358	521	10/18/2004	JV
358	522	10/18/2004	JV
358	523	10/19/2004	JV
358		10/18/2004	JV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Text search for CMYK, CYMK, control, K, gamut mapping, coverage restriction, limit, color transform, color transformation		JV
Color space transformation, conversion, color space conversion, color processing, color mapping, curved plane, convert		JV
converting, colorant, RGB, printing CIELAB images, CIELAB, CYMK, transformation, set K, controlling K, achromatic K, maximize		JV
maximum, color printing, maximize, maximum gamut, ink coverage, ink limitation, maximize, increase, color gamut, K, black		JV
out-of-gamut, mapping, minimum K, clipping K, clip, out-of-gamut mapping		JV
Using different combinations of operators : same, near, and, or, adj, with truncation		JV
Search was conducted from 10/22/2004 to 10/27/2004 using the above search strategy along with the class/subclass search.		JV

U.S. Patent and Trademark Office

Part of Paper No. 20041025

Search Notes (continued)	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/838,266	HIGASHIKATA ET AL.
	Examiner	Art Unit
	Jason D. A. Vuong	2626

SEARCHED

Class	Subclass	Date	Examiner
358	591	10/19/2004	JV
358	529	10/19/2004	JV
358		10/22/2004	JV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR